



EMF TEST REPORT

No. 2014EEB00060-EMF

For

ZTE Corporation

N9520 Wireless Charging Leather Cover、 Wireless Charging

Model Name: TWC010,TWC9520R

With

Hardware Version: A/0

Issued Date: April 17th, 2014

Note:

The test results in this test report relate only to the devices specified in this report. This report shall not be reproduced except in full without the written approval of TMC Beijing.

Test Laboratory:

TMC Beijing, Telecommunication Metrology Center of MIIT

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1. Test Laboratory

1.1 Testing Location

Company Name: TMC Shenzhen, Telecommunication Metrology Center of MIIT
Address: No. 12building, Shangsha Innovation and Technology Park, Futian District, Shenzhen, P. R. China
Postal Code: 518048
Telephone: +86-755-33322000
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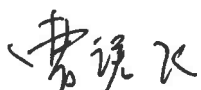
1.2 Testing Environment

Temperature: 18°C~25 °C,
Relative humidity: 30%~ 70%
Ground system resistance: < 0.5 Ω
Ambient noise & Reflection: < 0.012 W/kg

1.3 Project Data

Project Leader: Zhang Bojun
Test Engineer: Cao Junfei
Testing Start Date: April 08th, 2014
Testing End Date: April 15th, 2014

1.4 Signature



Cao Junfei
(Prepared this test report)



Zhang Bojun
(Reviewed this test report)



Lu Minniu
Director of the laboratory
(Approved this test report)

2 Client Information

2.1 Applicant Information

Company Name: ZTE Corporation
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2.2 Manufacturer Information

Company Name: ZTE Corporation
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Fax: +86-21-50801070

3 Equipment Under Test (EUT) and Ancillary Equipment (AE)

3.1 About EUT

Description:	N9520 Wireless Charging Leather Cover 、 Wireless Charging
Model name:	TWC010,TWC9520R
Marketing name:	/
Operating mode(s):	110kHz-205kHz
Device type:	Portable device
Accessories/Body-worn configurations:	/
Tested Tx Frequency:	110kHz-205kHz

3.2 Internal Identification of EUT

EUT ID*	SN or IMEI	HW Version	SW Version
EUT1	/	A/0	/

*EUT ID: is used to identify the test sample in the lab internally.

3.3 Internal Identification of AE

AE ID*	Description	Model	SN	Manufacturer
AE1	/	/	/	/

*AE ID: is used to identify the test sample in the lab internally.

4 Environmental evaluation and exposure limit

Environmental evaluation and exposure limit according to FCC CFR 47 part1,1.1307 (c) and (d) ,1.1310. According to FCC 1.1310: The criteria list in the following table shall be used to evaluate the Environment impact of human exposure to radio frequency(RF) radiation as specified in 1.1307 (c) and (d) .

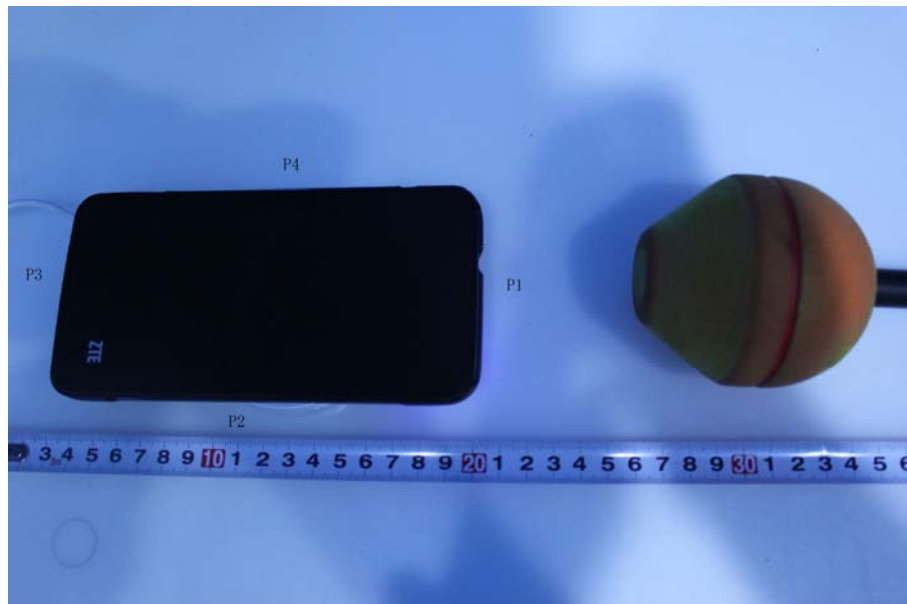
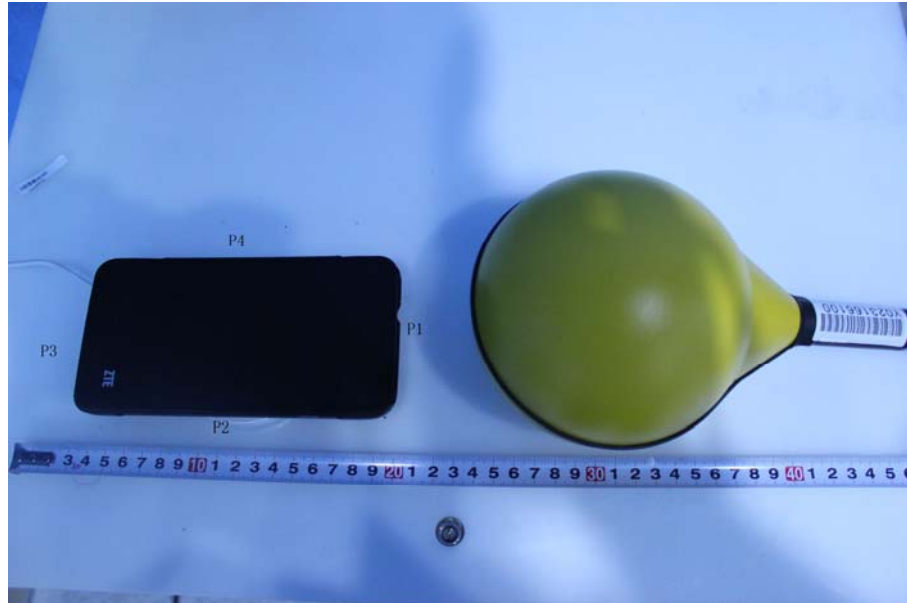
LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE(MPE)

Frequency Range (MHz)	Electric Field Strength(V/m)	Magnetic Field Strength(A/m)	Power density (Mw/cm)	Average Time (Minutes)
(A) Limits for Occupational/Control Exposure				
0.3-3.0	614	1.63	*(100)	6
(B) Limits for General Population/Unontrol Exposure				
0.-1.34	614	1.63	*(100)	30

*=Plane wave equivalent power density

5 TEST RESULT

5.1 Test setup



Note:

The RF exposure test is performed in the shield room.

The test distance is between the edge of charge and the geometric center of probe

The phone with specific receiver being charged by the transmitter during the field measurements.

The top of EUT is position 1, and the other edge of EUT is position 2 to position 4, when turned the EUT clockwise.

5.2 E-Field and H-Field Strength

Test Mode: Normal Operation (Charging Mode)

E-Field Strength at 10 cm from the edges surrounding the EUT

Frequency Range (MHz)	Probe Position 1 (V/m)	Probe Position 2 (V/m)	Probe Position 3 (V/m)	Probe Position 4 (V/m)	Limits (V/m)	PASS/ FAIL
110kHz-205kHz	0.84	0.89	0.77	0.93	614.0	PASS

H-Field Strength at 10 cm from the edges surrounding the EUT

Frequency Range (MHz)	Probe Position 1 (A/m)	Probe Position 2 (A/m)	Probe Position 3 (A/m)	Probe Position 4 (A/m)	Limits (A/m)	PASS/ FAIL
110kHz-205kHz	0.0150	0.0450	0.0116	0.0244	1.630	PASS

5.3 MAIN TEST INSTRUMENTS

No.	Manufacturer	Model	Serial no.	Calibrated date	Calibrated until
01	NARDA	2244/90.72	K-0011/AR0123	2014.4.1	2015.3.31
02	NARDA	2244/90.29	AB-0015/AR0123	2014.3.26	2015.3.25